

<i>Notice of References Cited</i>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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*	B	US-7,215,640	05-2007	Matsubara, Daisuke	370/235
*	C	US-2006/0182127	08-2006	Park, Ki-Beom	370/400
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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